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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/560,907	12/16/2005	Toshinori Sugihara	LB-1035-616	2364
	7590 04/28/201 NDERHYE, PC	EXAM	EXAMINER	
901 NORTH G	LEBE ROAD, 11TH F	KIM, JAY C		
ARLINGTON,	, VA 22203	ART UNIT	PAPER NUMBER	
		2815		
			MAIL DATE	DELIVERY MODE
			04/28/2011	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

## **Advisory Action** Before the Filing of an Appeal Brief

Ī	Application No.	Applicant(s)	
	10/560,907	SUGIHARA ET AL.	
	Examiner	Art Unit	
	JAY C. KIM	2815	

	JAY C. KIM	2815						
The MAILING DATE of this communication appe	ars on the cover sheet with the	correspondence add	ress					
THE REPLY FILED 15 April 2011 FAILS TO PLACE THIS APP	ICATION IN CONDITION FOR A	LOWANCE						
	. X The reply was filed after a final rejection, but prior to or on the same day as filing a Notice of Appeal. To avoid abandonment of this							
application, applicant must timely file one of the following	eplies: (1) an amendment, affidavi	t, or other evidence, w	hich places the					
application in condition for allowance; (2) a Notice of Appe								
for Continued Examination (RCE) in compliance with 37 C periods;	FR 1.114. The reply must be filed	within one of the follow	/ing time					
<ul> <li>a) The period for reply expires 3 months from the mailing date</li> </ul>	of the final rejection							
b) The period for reply expires on: (1) the mailing date of this A		in the final rejection, which	hever is later. In					
no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of the final rejection.								
Examiner Note: If box 1 is checked, check either box (a) or ( MONTHS OF THE FINAL REJECTION. See MPEP 706.07(i		FIRST REPLY WAS FIL	.ED WITHIN TWO					
Extensions of time may be obtained under 37 CFR 1.136(a). The date								
have been filed is the date for purposes of determining the period of ext under 37 CFR 1.17(a) is calculated from: (1) the expiration date of the s								
set forth in (b) above, if checked. Any reply received by the Office later								
may reduce any earned patent term adjustment. See 37 CFR 1.704(b).	·							
NOTICE OF APPEAL								
2. The Notice of Appeal was filed on A brief in comp								
filing the Notice of Appeal (37 CFR 41.37(a)), or any exter Notice of Appeal has been filed, any reply must be filed wi			appeal. Since					
AMENDMENTS	aniir the time penod set lotar in or	O11141.07(a).						
The proposed amendment(s) filed after a final rejection, by	ut prior to the date of filing a brief	will not be entered be	COLICA					
(a) They raise new issues that would require further cor			ouuse					
(b) They raise the issue of new matter (see NOTE below								
(c) They are not deemed to place the application in bett		ducing or simplifying th	ne issues for					
appeal; and/or								
<ul><li>(d) They present additional claims without canceling a c</li></ul>		ected claims.						
NOTE: <u>See Continuation Sheet</u> . (See 37 CFR 1.1)								
4. The amendments are not in compliance with 37 CFR 1.12		mpliant Amendment (i	°TOL-324).					
5. Applicant's reply has overcome the following rejection(s):								
Newly proposed or amended claim(s) would be all non-allowable claim(s).		•	-					
<ol> <li>For purposes of appeal, the proposed amendment(s): a) I how the new or amended claims would be rejected is prov</li> </ol>		l be entered and an ex	planation of					
The status of the claim(s) is (or will be) as follows:	idea below of appended.							
Claim(s) allowed:								
Claim(s) objected to:								
Claim(s) rejected: <u>4-34</u> . Claim(s) withdrawn from consideration:								
AFFIDAVIT OR OTHER EVIDENCE								
8. The affidavit or other evidence filed after a final action, but	hefore or on the date of filing a No	ntice of Anneal will not	he entered					
because applicant failed to provide a showing of good and								
was not earlier presented. See 37 CFR 1.116(e).								
9. The affidavit or other evidence filed after the date of filing								
entered because the affidavit or other evidence failed to o								
showing a good and sufficient reasons why it is necessary  10.   The affidavit or other evidence is entered. An explanation								
REQUEST FOR RECONSIDERATION/OTHER	TOT THE STATUS OF THE CHAIMS AFTER E	itry is below or attachi	au.					
11.  The request for reconsideration has been considered but	door NOT place the application in	condition for allowan	ao hagairea:					
See Continuation Sheet.	does not place the application if	condition for alloware	o because.					
12. Note the attached Information Disclosure Statement(s).	PTO/SB/08) Paper No(s).							
13. Other:								
_								
/J.K./	/Jay C Kim/							
	Examiner, Art Unit 2815							

Continuation of 3 NOTE: Declaration filed under Bule 132 will not be entered

Continuation of 11, does NOT place the application in condition for allowance because:

Applicants argue that "even though, Vilayakumar is only one of a combination of prior art references used in rejecting claims 4 and 5, however, Vilayakumar are deted specifically for the teaching of an added hydrogen dopant, and neither Vilayakumar or any of the other references teaches the claimed limitation that the added hydrogen has a concentration chosen to control the threshold voltage", and that "moreover, unlike the Examiner's assertion, claim 4 does receive specifically a correlation between concentrations of intentionally added dopants and a threshold voltage, "said active layer includes said nitrogen and hydrogen as intentionally added dopants having concentrations so that a threshold voltage of a gate voltage of the semiconductor device, when a voltage between a drain and a source region is fixed at 10V, is controlled to be substantially in a range between 0V and 3 V", emphasis added". (1) Intention to "control a threshold voltage" of a transistor by adding nitrogen and hydrogen is not a patentable subject matter. (2) Kanaski et al. in view of Goodman and further in view of Yan et al and further in view of Vilayakumar et al. and still further in view of Wager et al. disclose all the limitations of claims 4 and 5. (3) What Applicants suggest is that even though the combination of the references cannot be used to reject claims 4 and 5 because there is no explicit teaches claimed inventions of claims 4 and 5, the combination of the references cannot be used to reject claims 4 and 5 because there is no explicit teachesing of "controling a threshold voltage" of a transistor using nitrogen and hydrogen in the cited references. (4) It is not necessary that the prior art suggest the combination to achieve the same advantage or result discovered by applicant. See MPEP 2144.
Applicants arough that "the Examiner has not met his burden for providing a featual basis for his assertion that clied prior art teaches

intentionally adding htrogen and hydrogen having concentrations so that the threshold voltage lies within the claimed range"; and that the fact that other parameters may also affect the threshold voltage is inteneded, and the properties and the properties of the control of the properties and the properties of the control of the properties and the proper

Applicants argue that "first, even though Wager may teach a range for the threshold voltage within 1V-20V, however, the device of Wager is different than the claimed device, since Wager's device lacks a protective layer", that "the threshold voltage of a TFT having a protective layer is a lot different from that of a TFT without a protective layer, see p. 4 of Applicant's Response of November 11, 2010", that "it was the unexpected result of the inventors' work that showed that a TFT with a protective layer can have its threshold voltage within the practical range of 0V-3V, by controlling the concentrations of the nitrogen and hydrogen dopants", that "even though, controlling the threshold voltage of a field effect transistor may be well known in the art, the correlation between the concentrations of the intentionally added nitrogen and hydrogen and the claimed range for the threshold voltage in the claimed device with a cover was not known". These arguments are not convincing because of the following reasons. (1) in response to Applicants' arguments against the references individually, one cannot show nonobviousness by attacking references individually where the rejections are based on combinations of references. See In re Keller, 642 F.2d 413, 208 USPQ 871 (CCPA 1981); In re Merck & Co., 800 F.2d 1091, 231 USPQ 375 (Fed. Cir. 1986). (2) Wager et al. reference was used to show that a threshold voltage is a critical device parameter of a transistor that should be controlled, not to incorporate the whole structure of Wager et al. into the structure of Kawasaki et al. in view of Goodman and further in view of Yan et al. and further in view of Vijayakumar et al. (3) If the presence of the protective layer is critical in controlling the threshold voltage of the transistor, then Applicants should also claim the material composition and material properties of the protective layer unless "Applicants can provide an evidence that any type of a protective layer would result in the same threshold voltage of the transistor". In other words, if a threshold voltage of a transisor changes due to a different material of the protective layer, then each different material would require a different concentration of nitrogen and hydrogen for a desired threshold voltage, which may further require undue experimentation. (4) Applicants' arguments above are based on an assumption that Wager et al.'s transistor is the final structure and no other layers are formed on the transistor disclosed by Wager et al. This assumption is not convincing, especially when the transistor disclosed by Wager et al. should be packaged with other semiconductor or dielectric elements. Also the assumption is not convincing. because Applicants suggest that Wager et al, would measure a threshold voltage of their transistor without a protective layer anyway knowing that the threshold voltage would change subsequently after packaging of the transistor.

Applicants argue that "again, Wager's device lacks a protective cover, so it cannot be compared with the inventive device of claim 4", that "moreover, the fact that the claimed range for the threshold may be associated with certain device aparameters does not negate the fact that the concentrations of the added nitrogen and hydrogen cause the voltage threshold to lie in the claimed range of 0V to 3V (which is not taught or suggested by the cited prior art). These arguments are not convincing due to the following reasons. (1) See responses above regarding Wager et al. reference. (2) Wager et al. reference discloses a threshold voltage of about 1 to about 20 V, which overlaps the claimed threshold voltage.

Declaration filed April 15, 2011 will not be entered, because Applicants failed to provide a showing of good and sufficient reasons why the Declaration is necessary and was not earlier presented.